

## FDS9936A

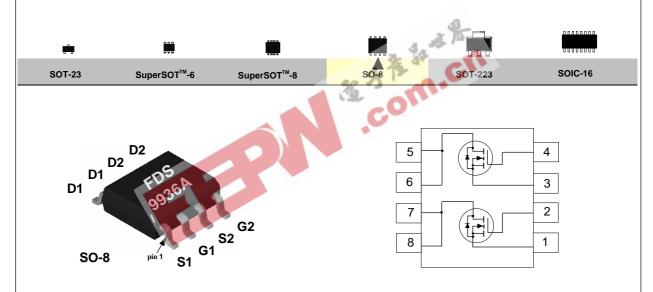
## **Dual N-Channel Enhancement Mode Field Effect Transistor**

# **General Description**

SO-8 N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to provide superior switching performance and minimize on-state resistance. These devices are particularly suited for low voltage applications such as disk drive motor control, battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

#### **Features**

- High density cell design for extremely low R<sub>DS(ON)</sub>.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package

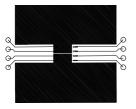


## **Absolute Maximum Ratings** $T_A = 25^{\circ}\text{C}$ unless other wise noted

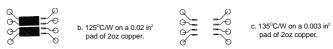
Symbol	Parameter	FDS9936A	Units
V <sub>DSS</sub>	Drain-Source Voltage	30	V
V <sub>GSS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub>	Drain Current - Continuous (Note 1a)	5.5	А
	- Pulsed	20	
$P_{D}$	Power Dissipation for Dual Operation	2	W
	Power Dissipation for Single Operation (Note 1a)	1.6	
	(Note 1b)	1	
	(Note 1c)	0.9	
$T_J$ , $T_{STG}$	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	L CHARACTERISTICS		
R <sub>eJA</sub>	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	°C/W
R <sub>euc</sub>	Thermal Resistance, Junction-to-Case (Note 1)	40	°C/W

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS	•				
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25 °C		32		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \ V_{GS} = 0 \text{ V}$			1	μA
		T <sub>J</sub> = 55°C			10	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
	CTERISTICS (Note 2)	•				
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1	1.5	3	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25 °C		-4.3		mV/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 5.5 \text{ A}$		0.03	0.04	Ω
		T <sub>J</sub> =125°C		0.046	0.068	
		$V_{GS} = 4.5 \text{ V}, I_D = 4.5 \text{ A}$		0.045	0.06	
D(ON)	On-State Drain Current	$V_{GS} = 10 \text{ V}, \ V_{DS} = 5 \text{ V}$	20			Α
Fs	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 4.7 \text{ A}$		7		S
OYNAMIC	CHARACTERISTICS	2 1 3 2	1			
Siss	Input Capacitance	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$ $V_{DS} = 5 \text{ V}, I_D = 4.7 \text{ A}$ $V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		350		pF
oss	Output Capacitance	f = 1.0 MHz		220		pF
rss	Reverse Transfer Capacitance	Co		80		pF
SWITCHING	CHARACTERISTICS (Note 2)					
D(on)	Turn - On Delay Time	$V_{DD} = 10 \text{ V}, I_{D} = 1 \text{ A},$		7.5	15	ns
	Turn - On Rise Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		12	25	
D(off)	Turn - Off Delay Time			13	25	
	Turn - Off Fall Time			6	15	
$Q_g$	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 5 \text{ A},$		12	17	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 10 V		2.1		
$Q_{gd}$	Gate-Drain Charge			2.6		
DRAIN-SOL	JRCE DIODE CHARACTERISTICS AND MAX	IMUM RATINGS				
S	Maximum Continuous Drain-Source Diode Forward Current				1.3	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.3 A (Note 2)		0.76	1.2	V

1.  $R_{g,h}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{g,C}$  is guaranteed by design while  $R_{g,C,h}$  is determined by the user's board design.



a. 78°C/W on a 0.5 in² pad of 2oz copper.





Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2.0%.

# **Typical Electrical Characteristics**

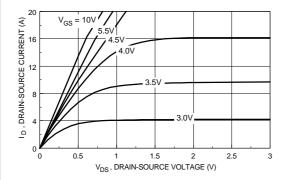


Figure 1. On-Region Characteristics.

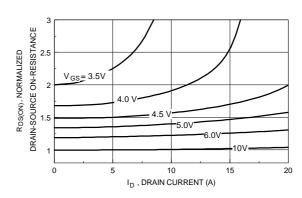


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

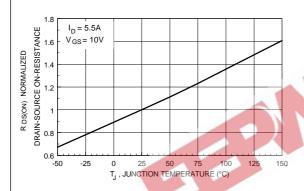


Figure 3. On-Resistance Variation with Temperature.

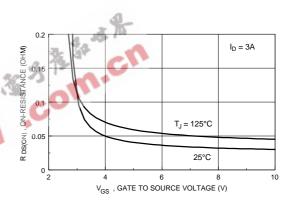


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

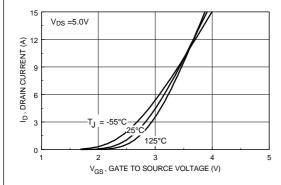


Figure 5. Transfer Characteristics.

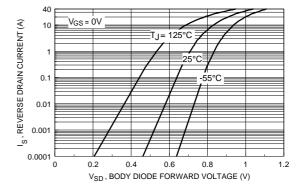
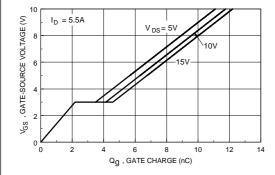


Figure 6 . Body Diode Forward Voltage Variation with Source Current and Temperature.

## Typical Electrical Characteristics (continued)



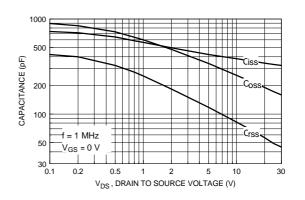
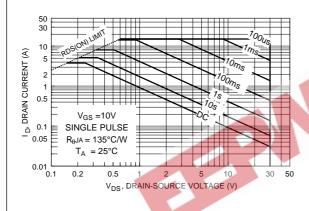


Figure 7. Gate Charge Characteristics.





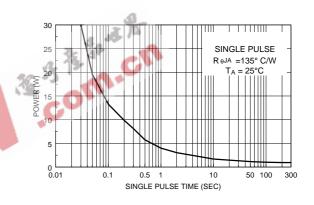


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

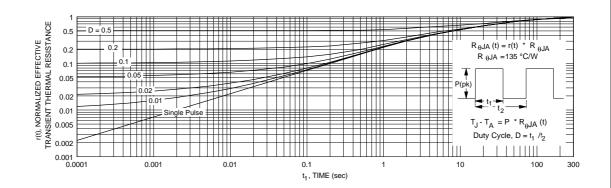
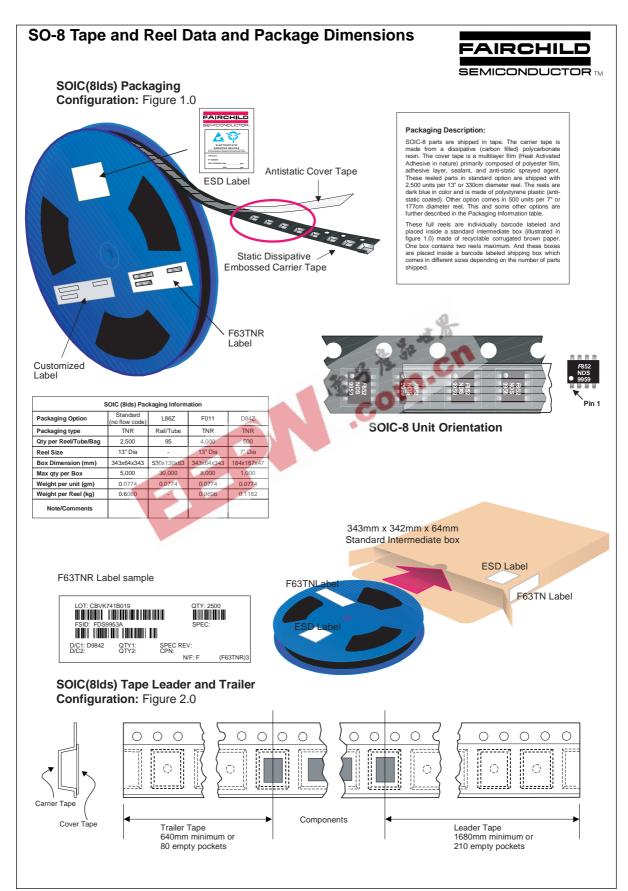
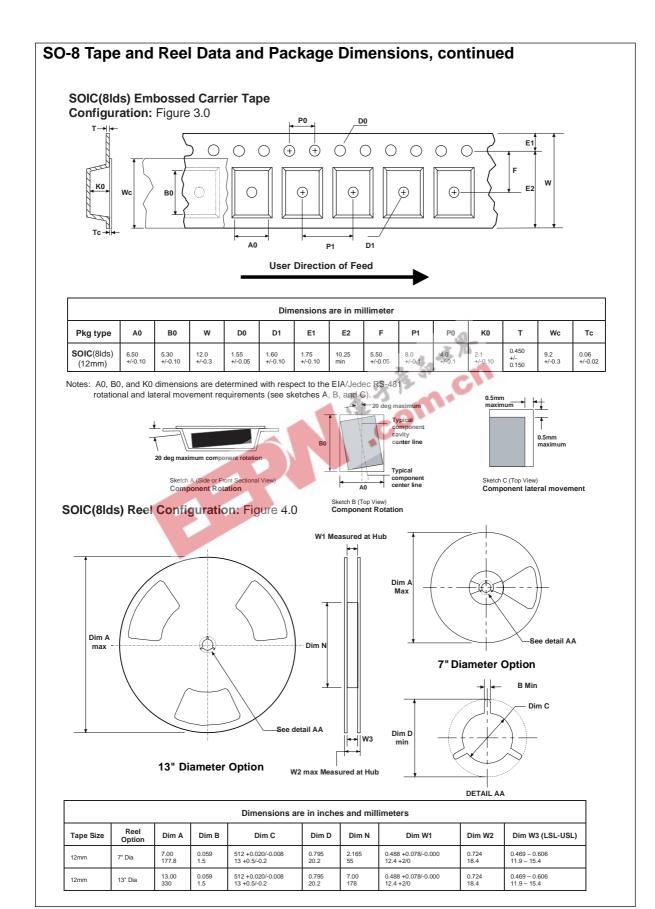
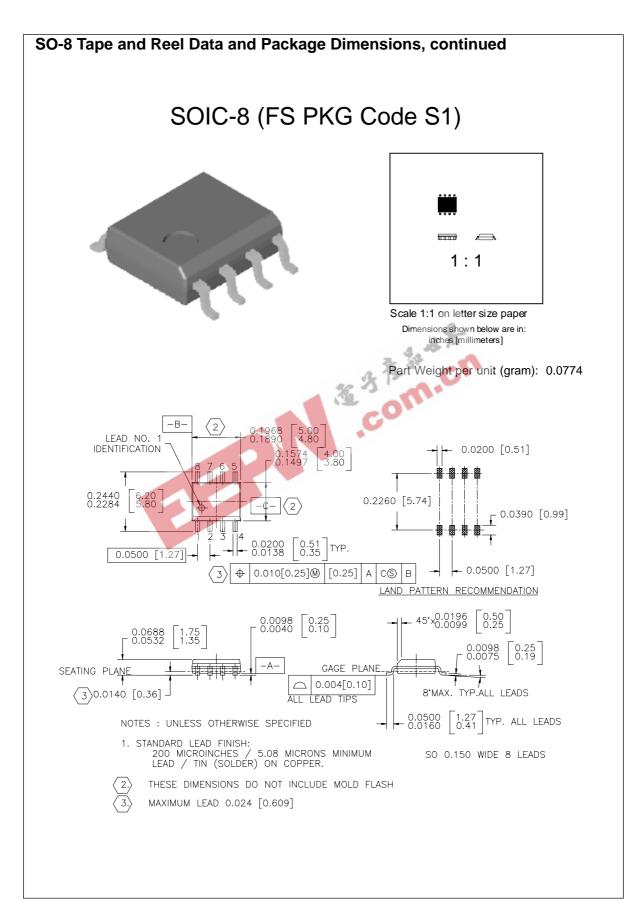


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.







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